

60V N-Channel SGT MOSFET

General Description

- Trench Power SGT technology
- Very low on-resistance R_{DS(ON)}
- Low Gate Charge
- $\bullet \quad \text{Excellent Gate Charge x $R_{DS(ON)}$ Product} \\$

Applications

• High Frequency Switching and Synchronous Rectification

Product Summary

 $\begin{array}{ll} V_{DS} & 60V \\ I_D \ (at \ V_{GS} = 10V) & 45A \\ R_{DS(ON)} \ (at \ V_{GS} = 10V) & < 15 m\Omega \\ R_{DS(ON)} \ (at \ V_{GS} = 4.5V) & < 19 m\Omega \end{array}$

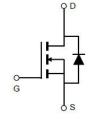
100% UIS Tested



DFN3x3







Part Number	Package Type	Form	Marking
TSG10N06ATC	DFN3×3	Tape & Reel	G10N06ATC

Absolute Maximum Ratings (T_A =25°C unless otherwise noted)

Parameter		Symbol	Maximum	Units
Drain-Source Voltage		V _{DS}	60	V
Gate-Source Voltage		V _{GS}	±20	V
Ocation of David Orange B	T _C =25°C		45	Δ.
Continuous Drain Current B	T _C =100°C	I _D	27	Α
Pulsed Drain Current A		I _{DM}	180	Α
Avalanche Current A		I _{AS}	20	Α
Single Pulse Avalanche Energy	L =0.3mH ^A	E _{AS}	20	mJ
Dower Dissipation C	T _C =25°C	В	56.5	W
Power Dissipation ^C	T _C =100°C	P _D	35.7	W
Junction and Storage Temperatu	re Range	T _J , T _{STG}	-55 to 175	°C
			•	

Thermal Characteristics

Parameter		Symbol	Maximum	Units
Maximum Junction-to-Case	Steady-State	$R_{\Theta JC}$	2.1	°C/W
Maximum Junction-to-Ambient	Steady-State	$R_{\Theta JA}$	50	-C/VV



Cumbal	Baramatar	Conditions		Value			
Symbol	Parameter			Min	Тур	Max	Units
STATIC PA	ARAMETERS						
BV _{DSS}	Drain-Source Breakdown Voltage	I _D =250μA,V _{GS} =0V		60			V
	Zee Oate Veltere Dusin Occurrent	V -60V V -0V	T _J =25°C			1	
I _{DSS}	Zero Gate Voltage Drain Current	V_{DS} =60V, V_{GS} =0V	T _J =125°C			100	μA
I_{GSS}	Gate-Body Leakage Current	$V_{DS} = 0V, V_{GS} = \pm 20V$				±100	nA
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$		1.1		2.5	V
	Ctatic Drain Course On Desistance	V _{GS} =10V, I _D =20A			12	15	mΩ
$R_{DS(ON)}$	Static Drain-Source On-Resistance	V _{GS} =4.5V, I _D =18A			15	19	mΩ
g _{FS}	Forward Transconductance	V _{DS} =5V, I _D =20A			100		S
V_{SD}	Diode Forward Voltage	I _S =1A, V _{GS} =0V				1	V
Is	Maximum Body-Diode Continuous Current B					30	Α
DYNAMIC	PARAMETERS					•	
C _{iss}	Input Capacitance				1134		
C _{oss}	Output Capacitance	$V_{GS} = 0V, V_{DS} = 30V, f = 1MH_Z$			123		pF
C _{rss}	Reverse Transfer Capacitance				12		
SWITCHIN	IG PARAMETERS						
Q _g (10V)	Total Gate Charge				21		
Q _g (4.5V)	Gate Source Charge	\/ -10\/\/ -20\/\	-204		11		-0
Q_{gs}	Gate Source Charge	- V _{GS} =10V,V _{DS} =30V, I _D =20A -			3.1		nC
Q_{gd}	Gate Drain Charge				5.1		
t _{D(on)}	Turn-On Delay Time				7		
t _r	Turn-On Rise Time	V_{GS} =10V, V_{DS} =30V, I_{D} =20A, R_{G} =3 Ω			3		- ns
$t_{D(off)}$	Turn-Off Delay Time				20		
t _f	Turn-Off Fall Time				3		
t _{rr}	Body Diode Reverse Recovery Time				17		ns
Q _{rr}	Body Diode Reverse Recovery Charge	-I _F =20A, di/dt =500A/μs			60		nC

- A. Single pulse width limited by maximum junction temperature.
- B. The maximum current rating is package limited.
- C. The power dissipation P_D is based on $T_{J(MAX)}$ =175°C, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.



Typical Characteristics $T_J = 25^{\circ}\text{C}$, unless otherwise noted

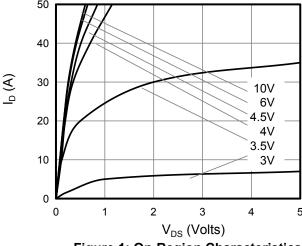


Figure 1: On-Region Characteristics Characteristics

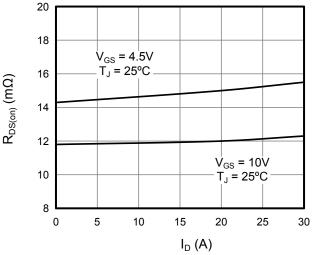


Figure 3: On-Resistance vs. Drain Current

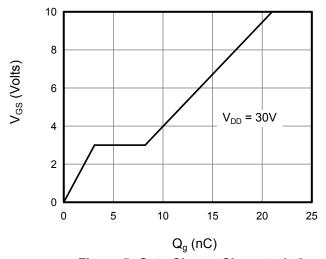


Figure 5: Gate Charge Characteristics

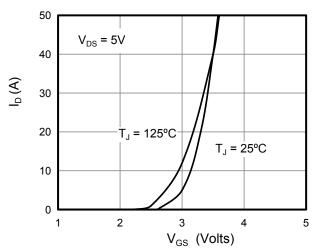


Figure 2: Transfer

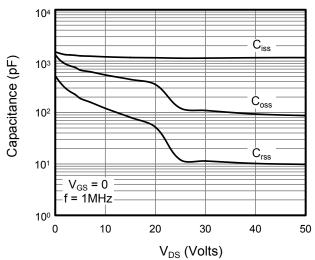


Figure 4: Capacitance Characteristics

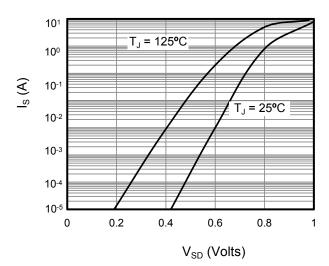
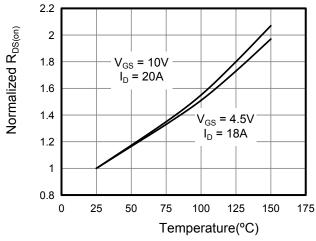


Figure 6: Body Diode Forward Voltage

Typical Characteristics $T_J = 25^{\circ}\text{C}$, unless otherwise noted



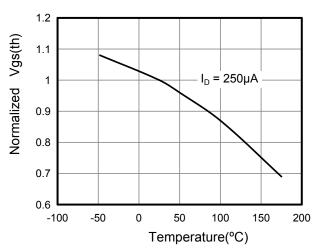
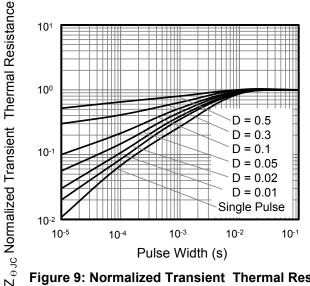


Figure 7: On-Resistance vs. Junction Temperature





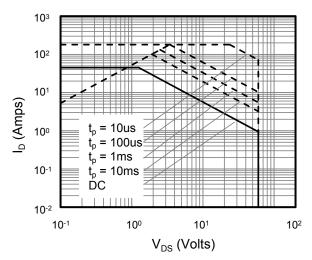


Figure 9: Normalized Transient Thermal Resistance

Figure 10: Safe Operating Area



Figure A: Gate Charge Test Circuit and Waveform

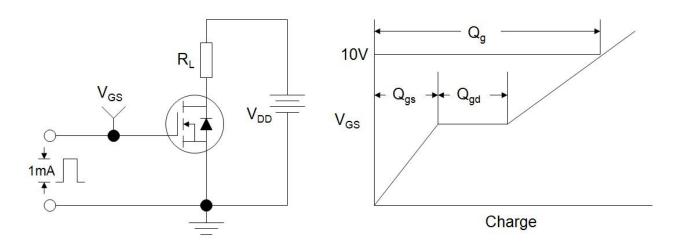


Figure B: Resistive Switching Test Circuit and Waveform

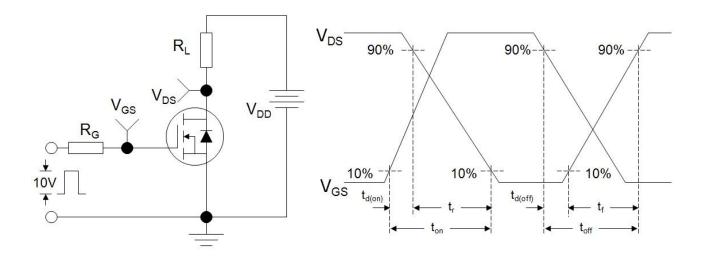
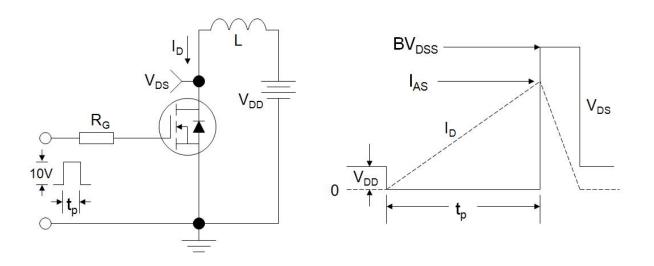
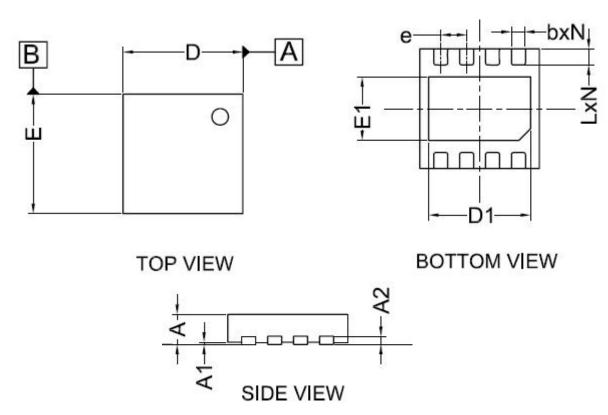


Figure C: Unclamped Inductive Switching Test Circuit and Waveform





DFN3×3



SYMBOL	MIN	TYP	MAX
A	0.70	0.75	0.80
A1	0.00	0.02	0.05
A2		0.203	
b	0.30	0.35	0.40
D	2.90	3.00	3.10
D1	2.51	2.56	2.61
E	2.90	3.00	3.10
E1	1.55	1.60	1.65
е	0.65BSC		
L	0.35	0.40	0.45
N		8	**



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